

<b>Search Notes</b>  	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10593786	KANO ET AL.
Examiner	Art Unit	
JON M LOCKARD	1647	

### SEARCHED

Class	Subclass	Date	Examiner
NONE		3/25/11	JML

### SEARCH NOTES

Search Notes	Date	Examiner
STIC Search of SEQ ID NOS:1-2. See sequence search results in SCORE.	3/25/11	JML
EAST (USPAT, US-PGPUB, EPO, DERWENT): See attached search history.	3/25/11	JML
STN (MEDLINE, SCISEARCH, EMBASE, BIOSIS): See attached search history.	3/25/11	JML
PALM: Inventor search.	3/25/11	JML

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner